

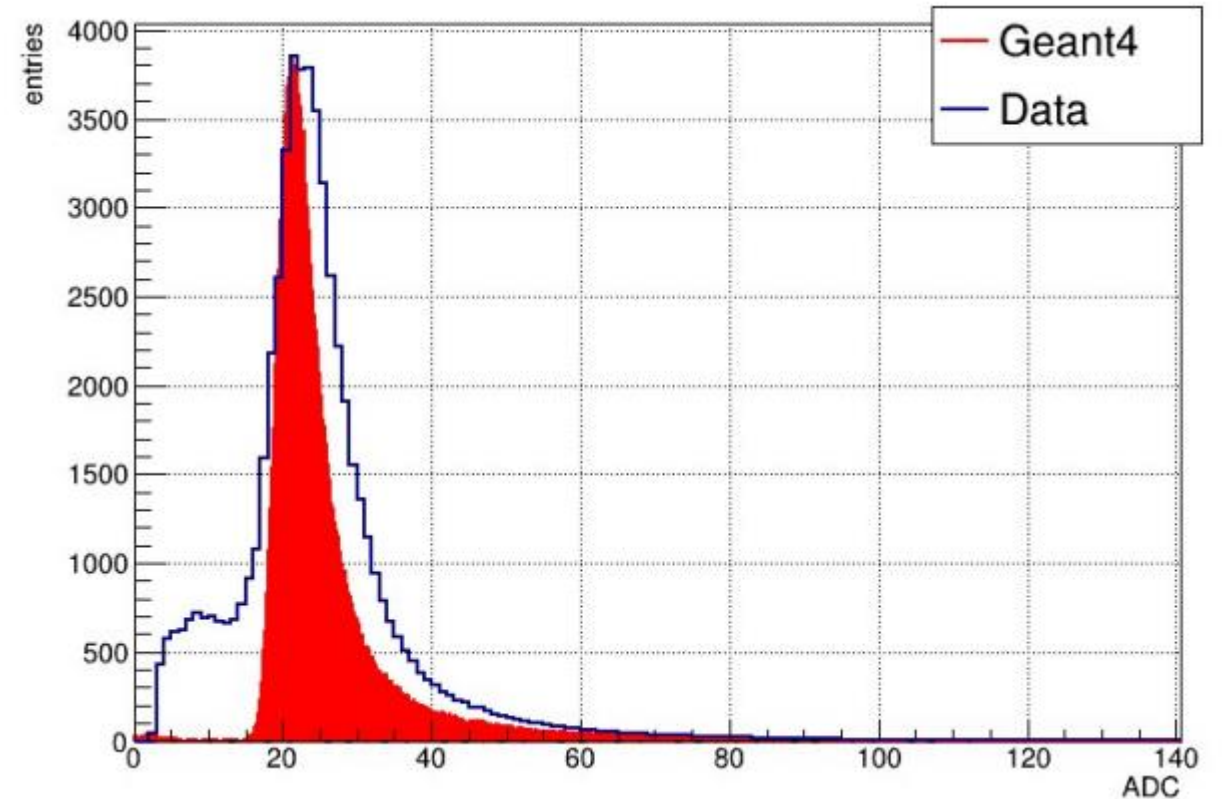
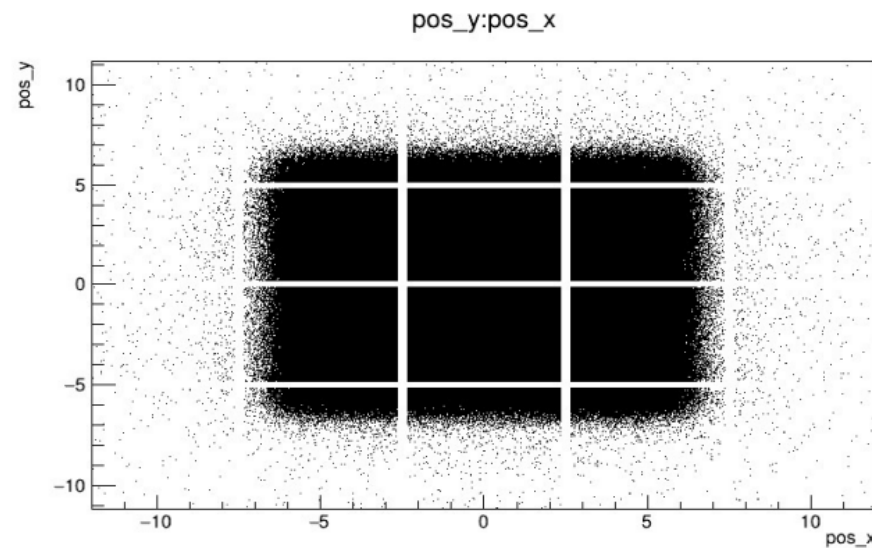
GaAs analysis and Geant4 simulation studies

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27/11/2024

Previous Simulation Results – Anton 1

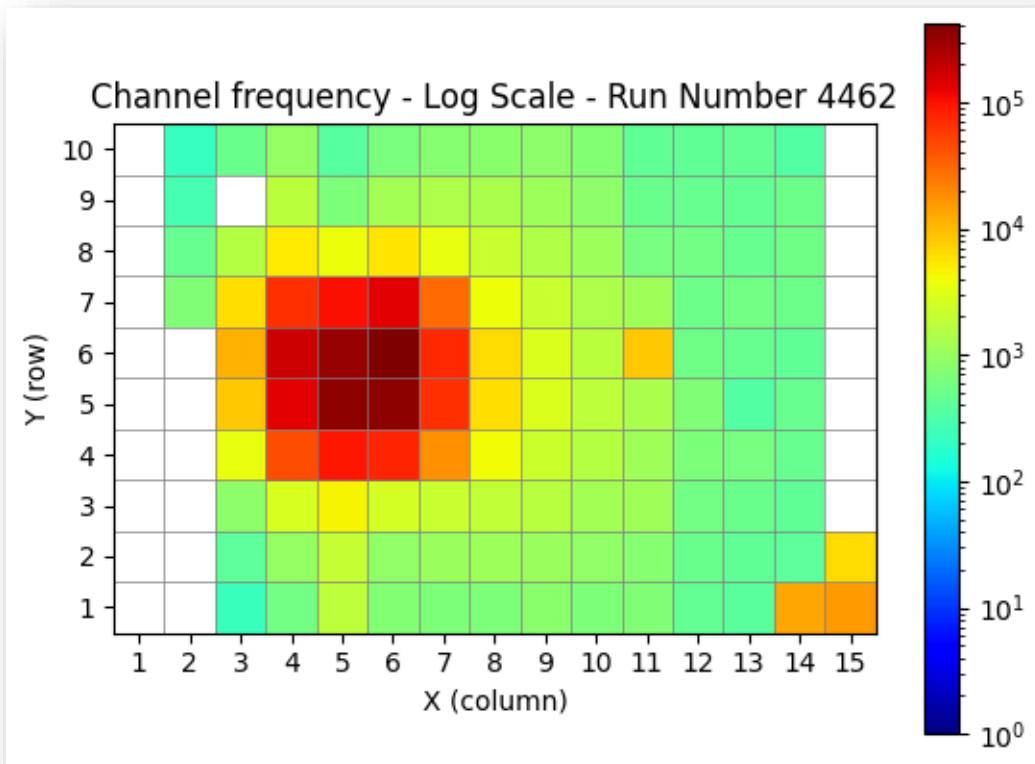
- 5GeV, e^-
- Square source 12mm \times 12mm
- 1M events
- Traces not yet simulated



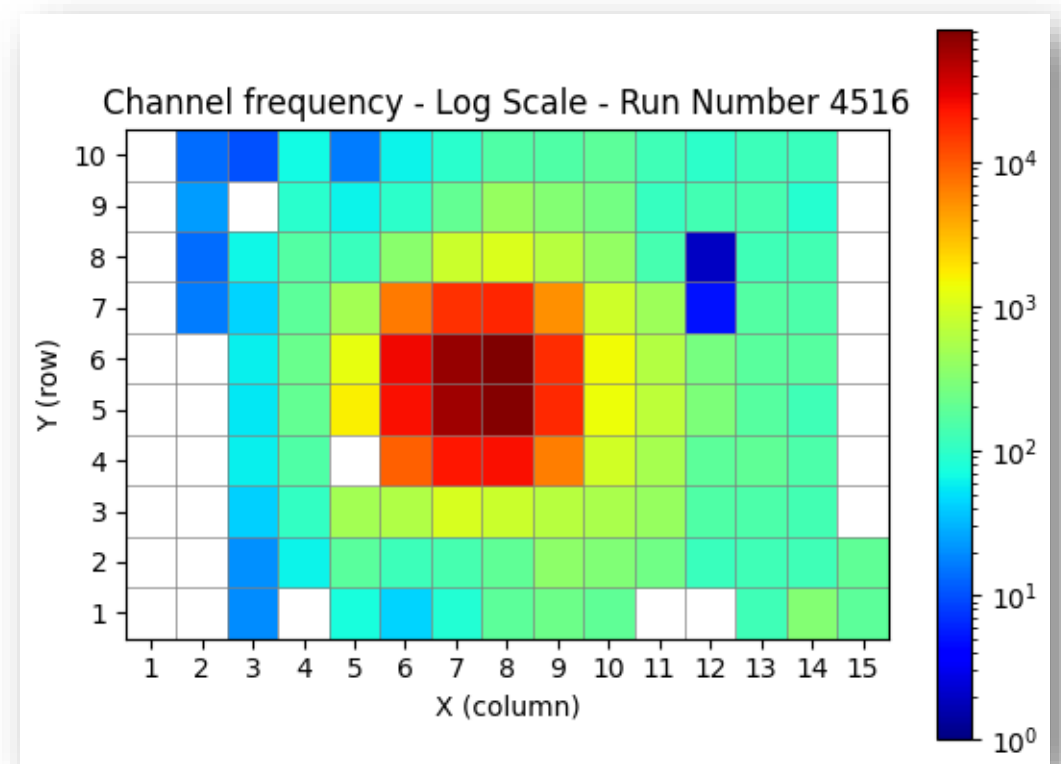
Experimental Data – Anton 1 vs Yan 1

Yan 1 seems to have more problematic channels

Anton 1



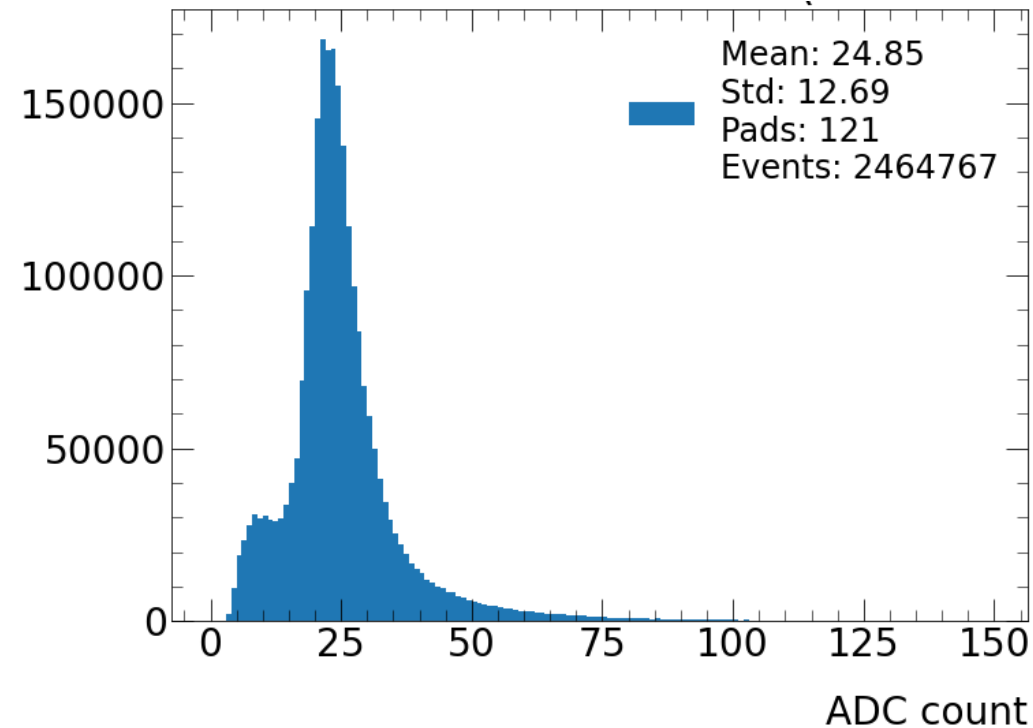
Yan 1



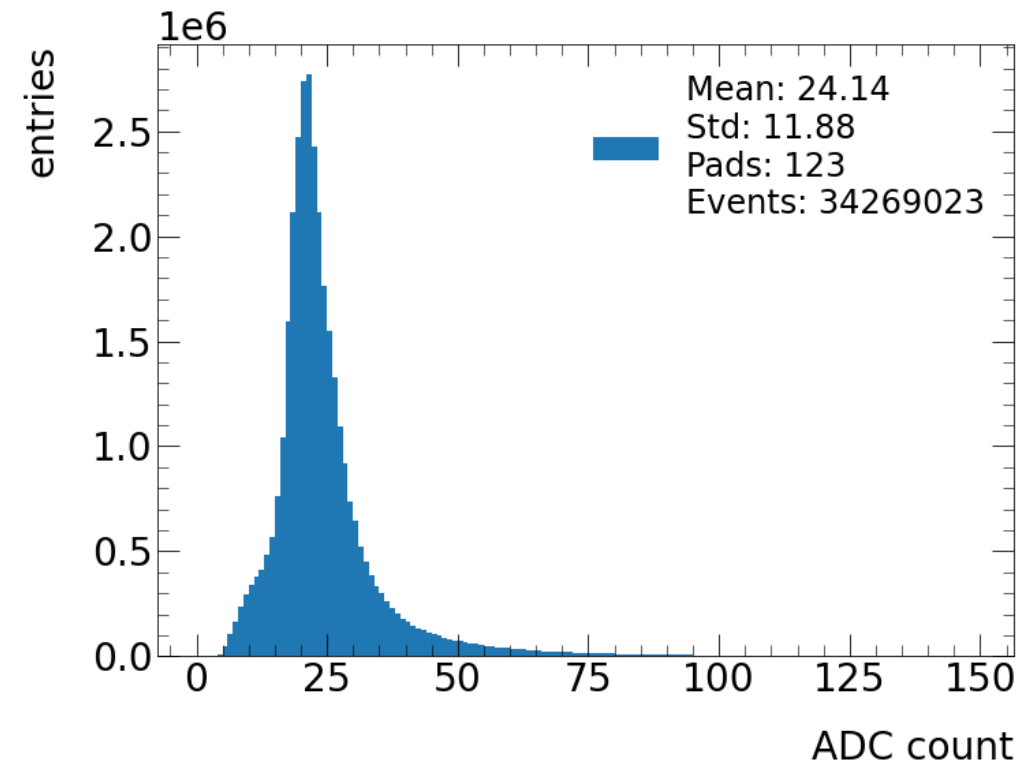
Experimental Data – Anton 1 vs Yan 1

Anton 1 has a larger “bump” in lower depositions

Anton 1

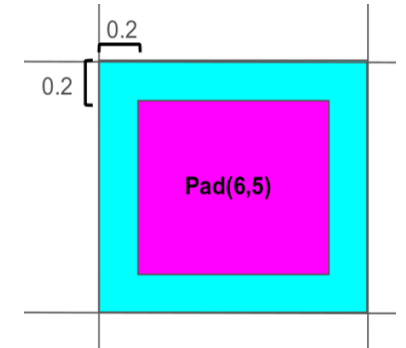


Yan 1

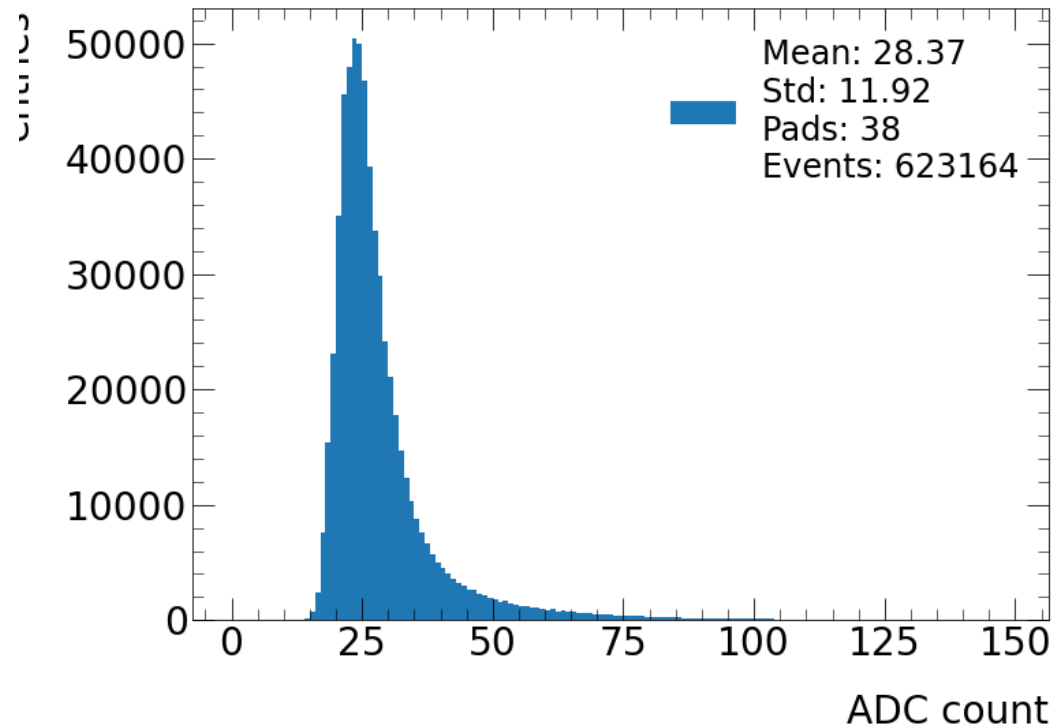


Experimental Data – Anton 1 vs Yan 1

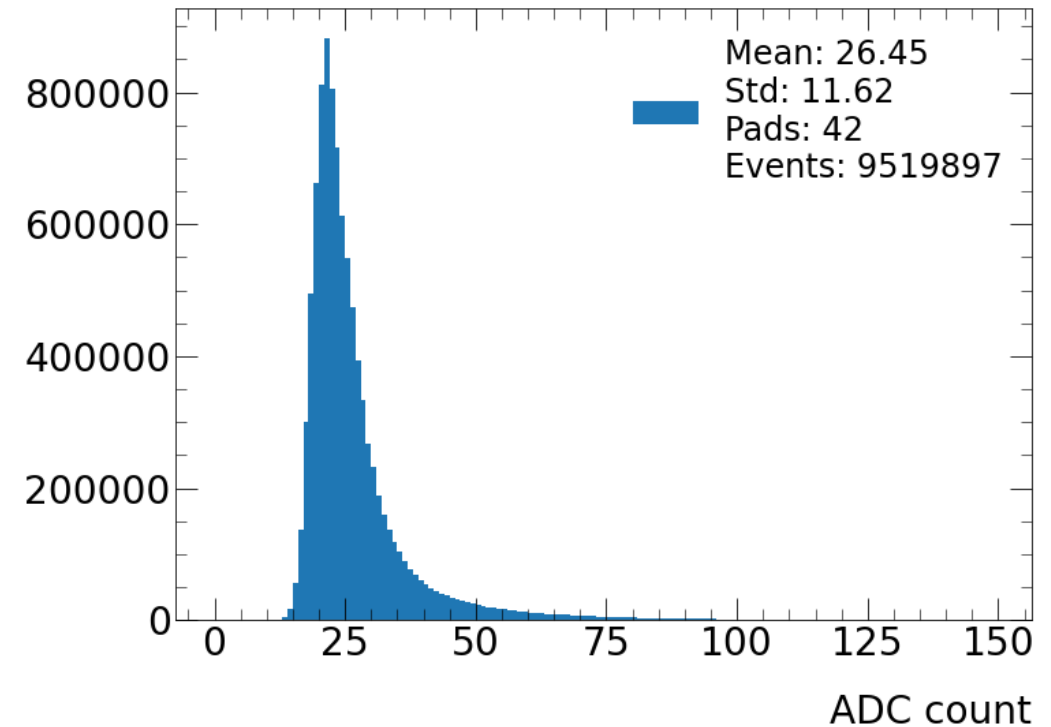
Taking only center of pad hits (20% margin) removes “bump”



Anton 1

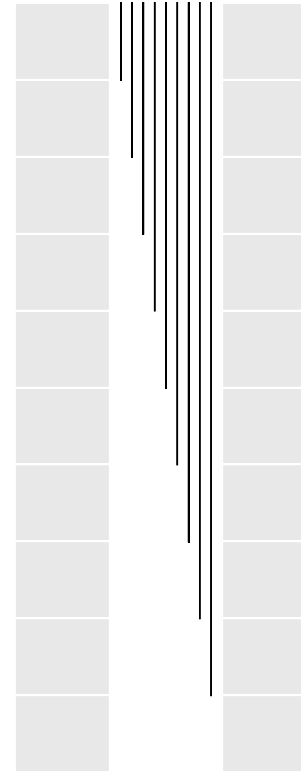


Yan 1

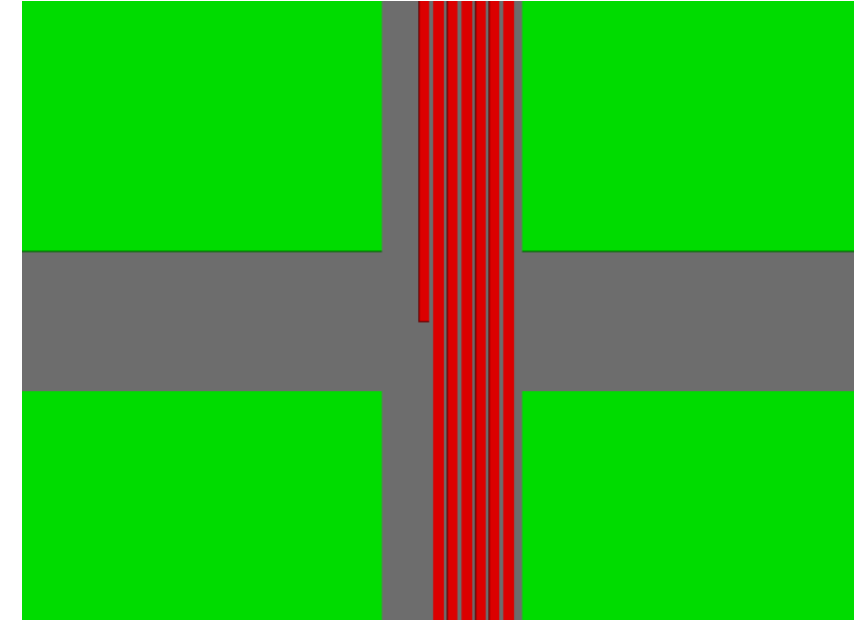


Current Simulation Results [WIP]

- 5GeV, e^-
- Square source 12mm \times 12mm
- 1M events
- Traces implemented:
 - Implemented as narrow Al sensitive pads
 - 9 straight traces of varying lengths between each 2 columns (total of 9x14)
 - Top area not simulated (above upper most row), as well as diagonal connection to corner of pad
 - Each trace begins in the middle of the vertical gap

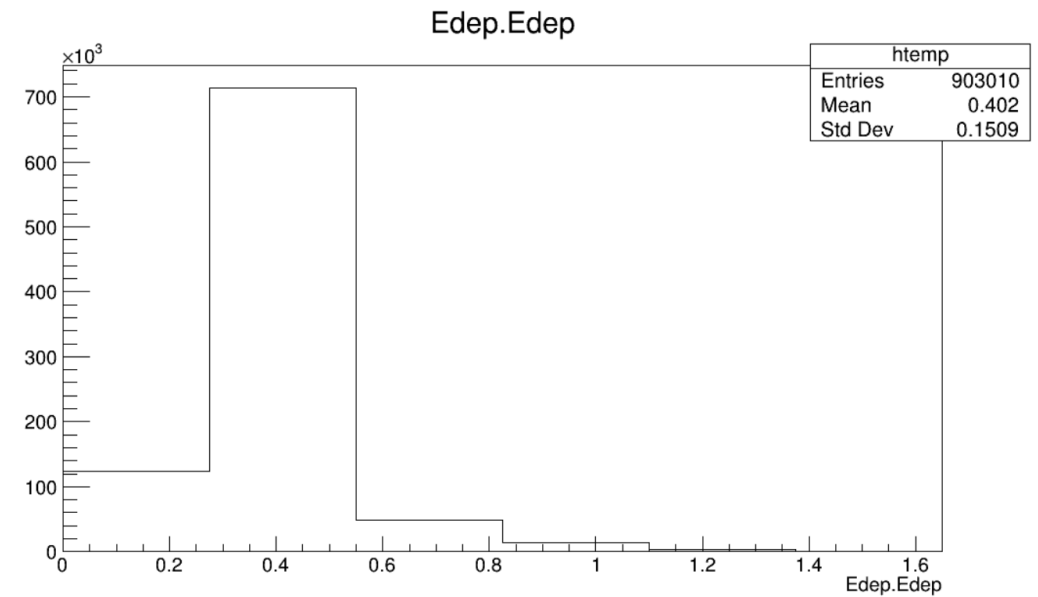
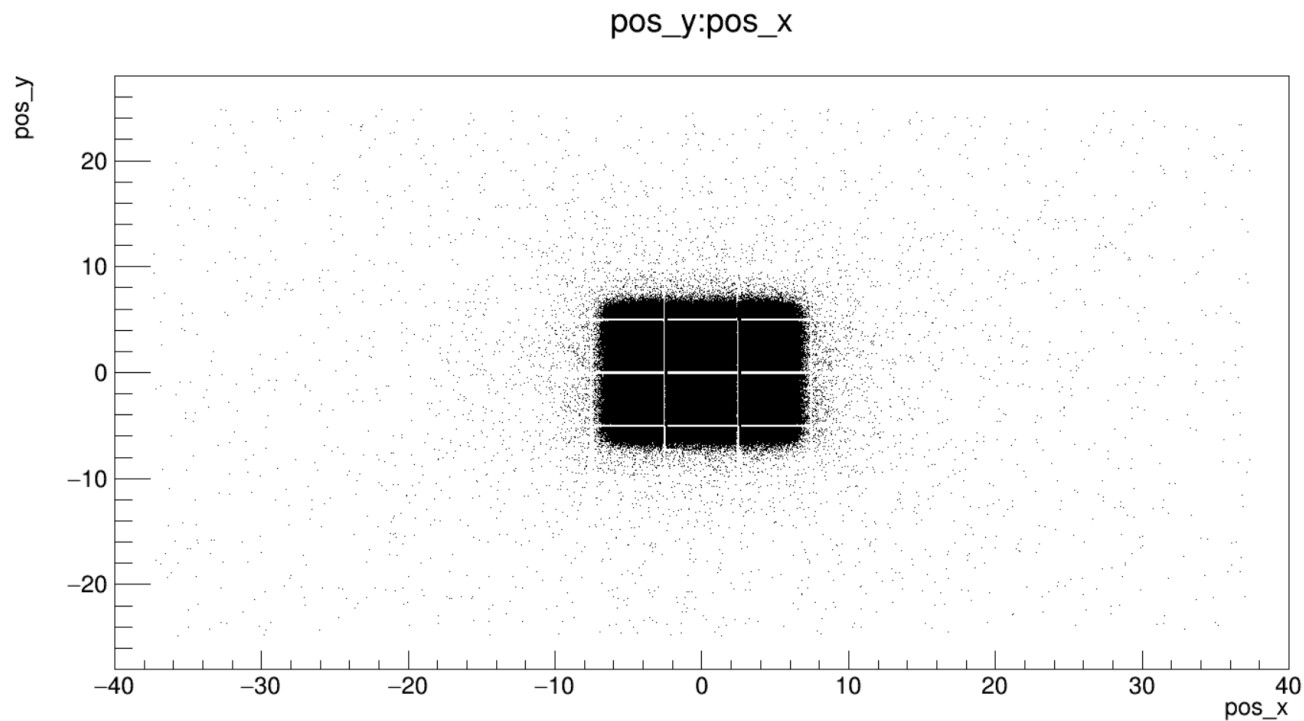


Traces implementation
sketch (not to scale)



Traces implementation
Geant4 Visualization
Green: pads
Red: traces

Current Simulation Results [WIP]



Prelim TBrowser hist
Very bad binning but shows first hints of
events with lower depositions

Ongoing tasks and conclusion

- Compare **center-of-pad** results between simulation and experimental data
- Compare between simulation **with traces** and **full data** (centered beam)
- Possible approach – **simulate digitization** in Geant4

Questions:

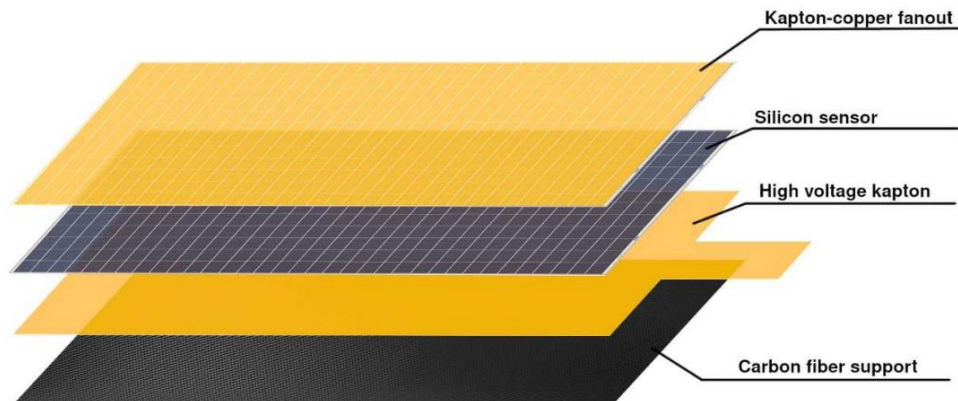
- Verify – GaAs layer is a wafer.
- Work done on Yan 1? (differences between Anton 1 and Yan 1)
- TB22 – GaAs backside facing beam

Backup

Sensors under investigation @ TB

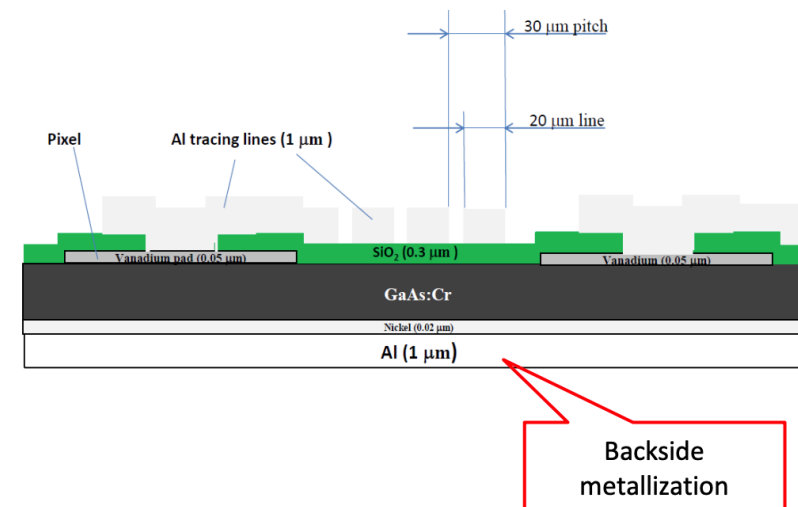
Silicon

- Produced by Hamamatsu (**CALICE** design)
- 500 μm thickness
- $5.5 \times 5.5 \text{ mm}^2$ pads, 10 μm gap
- External **Kapton fan-outs** with copper traces connected to the sensor pads with **conductive glue** (EPO-TEK E4110)



Gallium Arsenide

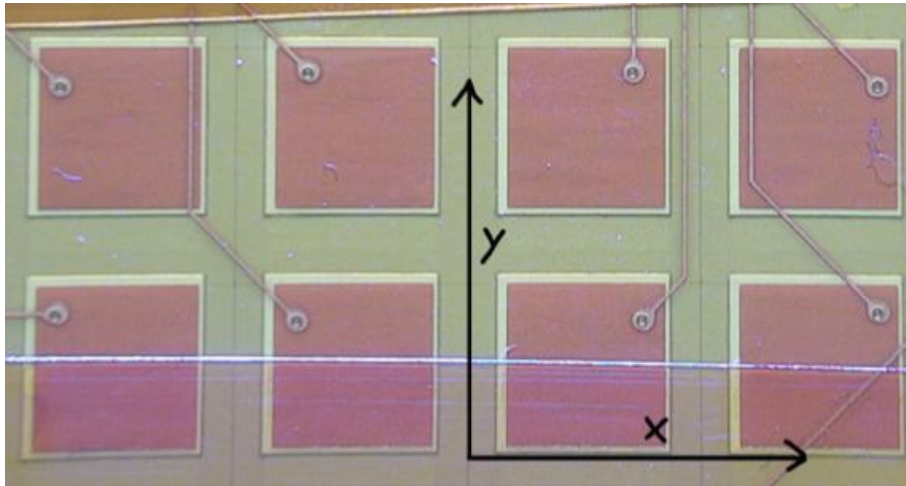
- Produced by National Research **Tomsk** State University
- 500 μm thickness
- $4.7 \times 4.7 \text{ mm}^2$ pads, 300 μm gap
- 10 μm Aluminum traces in the gaps, 20 μm apart from each other



Sensors under investigation @ TB

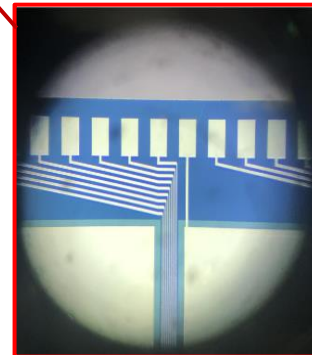
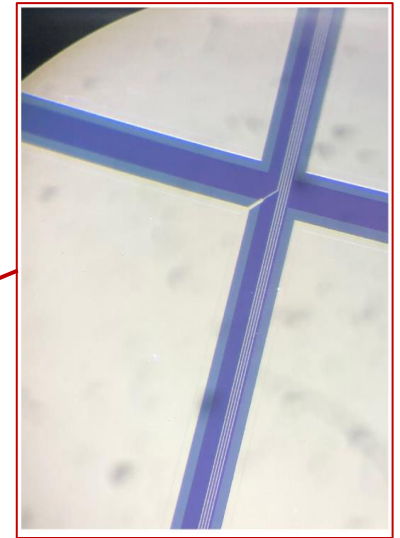
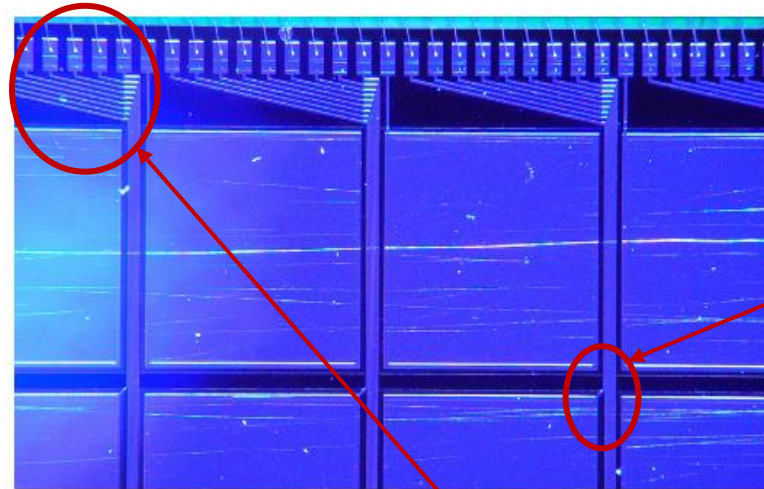
Silicon

- 16×8 pads



Gallium Arsenide

- 15×10 pads



Aluminum
Traces